# 5 kV<sub>rms</sub> 4.5-A/9-A Isolated Dual Channel Gate Driver

## Product Preview

# NCP51561

The NCP51561 are isolated dual-channel gate drivers with 4.5–A/9–A source and sink peak current respectively. They are designed for fast switching to drive power MOSFETs, and SiC MOSFET power switches. The NCP51561 offers short and matched propagation delays.

Two independent and 5 kV $_{rms}$  internal galvanic isolation from input to each output and internal functional isolation between the two output drivers allows a working voltage of up to 1500 V $_{DC}$ . This driver can be used in any possible configurations of two low side, two high–side switches or a half–bridge driver with programmable dead time.

An ENA/DIS pin shutdowns both outputs simultaneously when set low or high for ENABLE or DISABLE mode respectively.

The NCP51561 offers other important protection functions such as independent under-voltage lockout for both gate drivers and a Dead Time adjustment function.

#### **Features**

- 4.5 A Peak Source, 9 A Peak Sink Output Current Capability
- Flexible: Dual Low-Side, Dual High-Side or Half-Bridge Gate Driver
- Independent UVLO Protections for Both Output Drivers
- Output Supply Voltage from 9.5 V to 30 V with 8 V for MOSFET, 17 V UVLO for SiC, Thresholds
- Common Mode Transient Immunity CMTI > 200 V/ns
- Propagation Delay Typical 36 ns with
  - 8 ns Max Delay Matching per Channel
  - 8 ns Max Pulse–Width Distortion
- User Programmable Input Logic
  - Single or Dual-Input Modes via ANB
  - ◆ ENABLE or DISABLE Mode
- User Programmable Dead-Time
- Isolation & Safety
  - 5 kV<sub>rms</sub> Galvanic Isolation from Input to Each Output and 1500 V Peak Differential Voltage between Output Channels
  - 1200 V Working Voltage (per VDE0884–11 Requirements)
- These are Pb-Free Devices

#### **Typical Applications**

- Motor Drives
- Isolated Converters in DC–DC and AC–DC Power Supply
- Server, Telecom, and Industrial Infrastructures
- UPS and Solar Inverters

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SOIC-16 WB CASE 751G-03

#### **MARKING DIAGRAM**



NCP51561 = Specific Device Code

X = B or D for UVLO Option

Y = A or B for ENABLE/DISABLE A = Assembly Location

WL = Wafer Lot

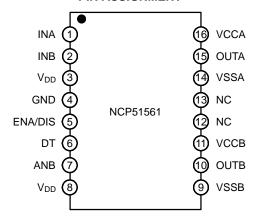
YY = Year

WW = Work Week

G

#### **PIN ASSIGNMENT**

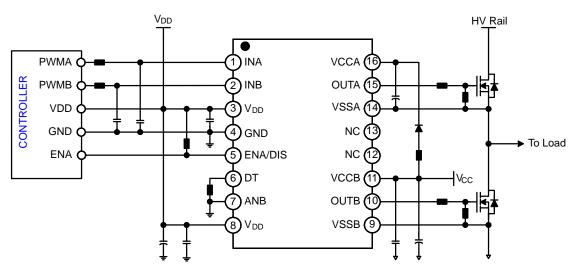
= Pb-Free Package



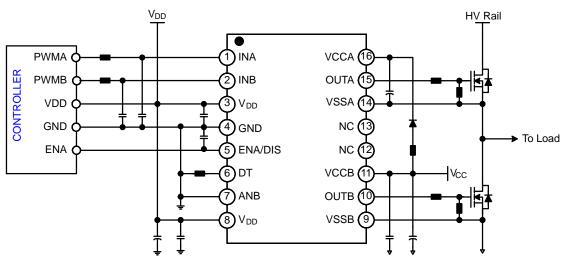
#### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 28 of this data sheet.

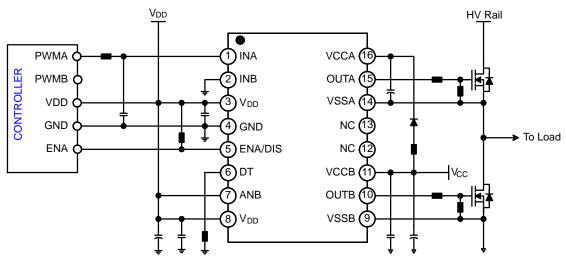
#### **TYPICAL APPLICATION CIRCUIT**



(a) High and Low Side MOSFET Gate Drive for ENABLE Version



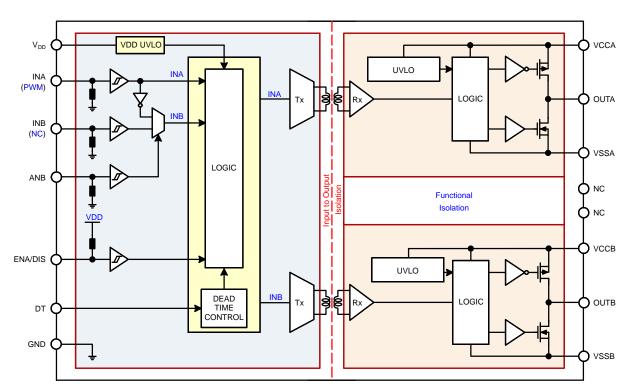
(b) High and Low Side MOSFET Gate Drive for DISABLE Version



(c) High and Low Side MOSFET Gate Drive with PWM Controller for ENABLE Version

Figure 1. Application Schematic

#### **FUNCTIONAL BLOCK DIAGRAM**



(a) For Only ENABLE (NCP51561xA) Version

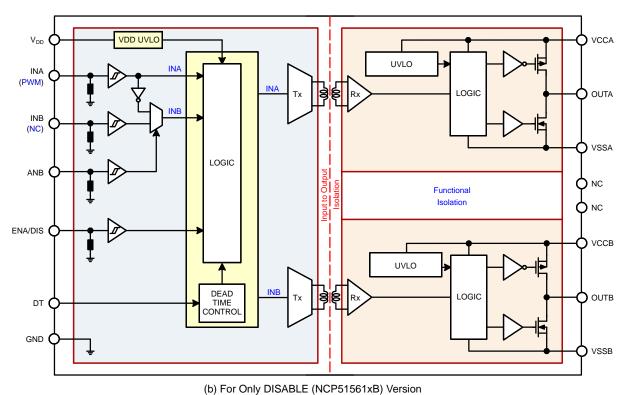


Figure 2. Simplified Block Diagram

#### **FUNCTIONAL TABLE**

	INPUT				UVLO			GATE DRIVE OUTPUT	
ENA/DIS	(Note 3)					Outpu	t Side		
ENABLE	DISABLE	ANB	INA	INB	Input Side (V <sub>DD</sub> )	Channel A (V <sub>CCA</sub> )	Channel B (V <sub>CCB</sub> )	OUTA	OUTB
Х	Х	Х	Х	Х	Active	Х	Х	L	L
Х	Х	Х	Х	Х	Х	Active	Active	L	L
Н	L	L	Х	L	Inactive	Active	Inactive	L	L
Н	L	L	Х	Н	Inactive	Active	Inactive	L	Н
Н	L	L	L	Х	Inactive	Inactive	Active	L	L
Н	L	L	Н	Х	Inactive	Inactive	Active	Н	L
L	Н	L	Х	Х	Inactive	Inactive	Inactive	L	L
Н	L	L	L	L	Inactive	Inactive	Inactive	L	L
Н	L	L	L	Н	Inactive	Inactive	Inactive	L	Н
Н	L	L	Н	Н	Inactive	Inactive	Inactive	L (Note 5)	L (Note 5)
					Inactive	Inactive	Inactive	H (Note 6)	H (Note 6)
Н	L	Н	L	Х	Inactive	Active	Inactive	L	Н
Н	L	Н	Н	Х	Inactive	Active	Inactive	L	L
Н	L	Н	L	Х	Inactive	Inactive	Active	L	L
Н	L	Н	Н	Х	Inactive	Inactive	Active	Н	L
L	Н	Н	Х	Х	Inactive	Inactive	Inactive	L	L
Н	L	Н	L	Х	Inactive	Inactive	Inactive	L	Н
Н	L	Н	Н	Х	Inactive	Inactive	Inactive	Н	L

- "L" means that LOW, "H" means that HIGH and X: Any Status
   Inactive means that V<sub>DD</sub>, V<sub>CCA</sub>, and V<sub>CCB</sub> are above UVLO threshold voltage (Normal operation)
   Active means that UVLO disables the gate driver output stage.
   Disables both gate drive output when the ENA/DIS pin is LOW in ENABLE version, which is default is HIGH, if this pin is open.
   Enables both gate drive output when the ENA/DIS pin is LOW in DISABLE version, which is default is LOW, if this pin is open.
   When the ANB pin is HIGH, OUTA and OUTB are complementary outputs from PWM input signal on the INA pin regardless the INB signal.
- 5. DT pin is left open Or programmed with R<sub>DT</sub>.
- 6. DT pin pulled to V<sub>DD</sub>.

#### **PIN CONNECTIONS**

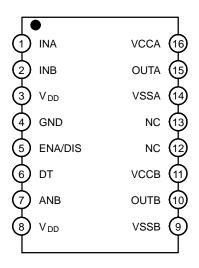


Figure 3. Pin Connections – SOIC-16 WB (Top View)

#### **PIN DESCRIPTION**

Pin No.	Symbol	I/O	Description
1	INA	Input	Logic Input for Channel A with internal pull-down resistor to GND
2	INB	Input	Logic Input for Channel B with internal pull-down resistor to GND.
3, 8	V <sub>DD</sub>	Power	Input–side Supply Voltage. It is recommended to place a bypass capacitor from V <sub>DD</sub> to GND.
4	GND	Power	Ground Input-side. (all signals on input-side are referenced to this pin)
5	ENA/DIS	Input	Logic Input High Enables Both Output Channels with Internal pull-up resistor for an ENABLE version. Conversely, Logic Input High disables Both Output Channels with Internal pull-down resistor for the DISABLE version.
6	DT	Input	Input for programmable Dead–Time It provides three kind of operating modes according to the DT pin voltage as below.
7	ANB	Input	Logic Input to change the input signal configuration with internal pull–down resistor to GND. OUTA and OUTB work as complementary outputs from INA PWM input signal regardless of the INB signal when the ANB pin is high. It is recommended to tie this pin to GND or floating (not recommended) if the ANB pin is not used to achieve better noise immunity.  The ANB pin should be kept low when the OUTA and OUTB are controlled individually via INA and INB pins. The ANB pin has a typical 3.3 µs internal filter to improve noise immunity but we recommend to tie to GND.
9	VSSB	Power	Ground for Channel B
10	OUTB	Output	Output for Channel B
11	V <sub>CCB</sub>	Power	Supply Voltage for Output Channel B. It is recommended to place a bypass capacitor from V <sub>CCB</sub> to VSSB.
12, 13	NC	-	No Connection; Keep pin floating
14	VSSA	Power	Ground for Channel A
15	OUTA	Output	Output of Channel A
16	V <sub>CCA</sub>	Power	Supply Voltage for Output Channel A. It is recommended to place a bypass capacitor from V <sub>CCA</sub> to VSSA.

#### **SAFETY AND INSULATION RATINGS**

Symbol	Parameter		Min.	Тур.	Max.	Unit
		< 150 VRMS		I–IV		
	Installation Classifications per DIN VDE 0110/1.89 Table 1 Rated Mains Voltage	< 300 VRMS		I–IV		
		< 450 VRMS		I–IV		
		< 600 VRMS		I–IV		
		< 1000 VRMS		I–III		
	Comparative Tracking Index (DIN IEC 112/VDE 030	3 Part 1)	600			
CTI	Climatic Classification			40/100/21		
	Pollution Degree (DIN VDE 0110/1.89)			2		
VPR	Input – to – Output Test Voltage, Method b, VIORM × Production Test with tm = 1 s, Partial Discharge < 5 p		2250			V <sub>PK</sub>
VIORM	Maximum Operation Insulation Voltage		1200			V <sub>PK</sub>
VIOTM	Maximum Transient Over Voltage		8400			$V_{PK}$
Ecr	External Creepage		8.0			mm
Ecl	External Clearance		8.0			mm
DTI	Insulation Thickness		17.3			um
Rio	Insulation Resistance at T <sub>S</sub> , VIO = 500 V		10 <sup>9</sup>			Ω
JL1577	-					
Viso	Withstand isolation voltage $V_{TEST} = V_{ISO} = 5000 V_{RMS}, t = 60 V_{TEST} = 1.2 \times V_{ISO} = 6000 V_{RMS}, t = 10 V_{TEST} = 1.2 \times V_{ISO} = 6000 V_{RMS}, t = 10 V_{TEST} = 1.2 \times V_{ISO} = 6000 V_{RMS}, t = 10 V_{TEST} = 1.2 \times V_{ISO} = 6000 V_{RMS}, t = 10 V_{TEST} = 1.2 \times V_{ISO} = 6000 V_{RMS}, t = 10 V_{TEST} = 1.2 \times V_{ISO} = 6000 V_{RMS}, t = 10 V_{TEST} = 1.2 \times V_{$		5000			V <sub>RMS</sub>

#### **SAFETY RELATED CERTIFICATION**

UL	CSA	VDE	CQC
Certified according to UL 1577 Component Recognition Program	Approved under CSA Component Acceptance Notice 5A, IEC 60950–1 and IEC 60601–1		Certified according to GB 4943.1–2011
Single protection, 5000 VRMS	Reinforced insulation per CSA 60950–1–07+A1+A2 and IEC 60950–1 2nd Ed.	Reinforced Insulation Maximum Transient Isolation voltage, 8000Vpк; Maximum Repetitive Peak Isolation Voltage, 2121 Vpк; Maximum Surge Isolation Voltage, 8000 Vpк	Reinforced Insulation, Altitude ≤ 5000 m, Tropical Climate
File number: E509109	Agency Qualification Planned	Agency Qualification Planned	Agency Qualification Planned

#### **SAFETY LIMITING VALUE**

Symbol	Parameter	Test Condition	Side	Min.	Тур.	Max.	Unit
I <sub>S</sub>	Safety output supply current	$R_{\theta JA}$ = 81 °C/W, VCCA = VCCB = 12 V, $T_A$ = 25 °C, $T_J$ =150 °C See Figure 4	DRIVER A, DRIVER B			61	mA
		$R_{\theta JA}$ = 81 °C/W, VCCA = VCCB = 25 V, $T_A$ = 25 °C, $T_J$ =150 °C See Figure 4	DRIVER A, DRIVER B			29	mA
P <sub>S</sub>	Safety supply power	$R_{\theta JA} = 81 \text{ °C/W}, T_A = 25 \text{ °C}, T_J = 150 \text{ °C}$	INPUT			60	mW
		See Figure 5	DRIVER A			720	
			DRIVER A			720	
			TOTAL			1500	
T <sub>S</sub>	Safety temperature					150	°C

#### **MAXIMUM RATINGS**

Symbol		Parameter	Min	Max	Unit
V <sub>DD</sub> to	GND	Power Supply Voltage – Input Side (Note 8)	-0.3	5.5	V
V <sub>CCA</sub> – VSSA,	V <sub>CCB</sub> – VSSB	Power Supply Voltage – Driver Side (Note 9)	-0.3	33	V
OUTA to VSSA,	OUTB to VSSB	Driver Output Voltage (Note 9)	-0.3	V <sub>CCA</sub> + 0.3, V <sub>CCB</sub> + 0.3	V
	OUTB to VSSB, 00 ns (Note 10)		-2	V <sub>CCA</sub> + 0.3, V <sub>CCB</sub> + 0.3	V
INA, INB,	and ANB	Input Signal Voltages (Note 8)	-0.3	20	V
	sient for 50 ns e 10)		-5	20	V
ENA	/DIS	Input Signal Voltages (Note 8)	-0.3	5.5	V
	nsient for 50ns e 10)		-5	5.5	V
D	T	Dead Time Control (Note 8)	-0.3	V <sub>DD</sub> + 0.3	V
V <sub>I</sub>	SO	Input to Output Isolation Voltage	-5000	5000	$V_{RMS}$
VSSA-VSSB,	VSSB-VSSA	Channel to Channel Voltage	_	1500	V
T <sub>J</sub>		Junction Temperature	-40	+150	°C
T <sub>S</sub>		Storage Temperature	-65	+150	°C
Electrostatic	HBM (Note 11)	Human Body Model	-	±4	kV
Discharge Capability	CDM (Note 11)	Charged Device Model	-	±2	V

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality

- should not be assumed, damage may occur and reliability may be affected.

  7. Refer to ELECTRICAL CHARACTERISTICS, RECOMMENDED OPERATING RANGES and/or APPLICATION INFORMATION for Safe Operating parameters.

  8. All voltage values are given with respect to GND pin.

- All voltage values are given with respect to VSSA or VSSB pin.
   This parameter verified by design and bench test, not tested in production.
   This device series incorporates ESD protection and is tested by the following methods:
  - ESD Human Body Model tested per AEC-Q100-002 (EIA/JESD22-A114)
  - ESD Charged Device Model tested per AEC-Q100-011 (EIA/JESD22-C101)
  - Latch up Current Maximum Rating: ≤100 mA per JEDEC standard: JESD78, 25°C

#### RECOMMENDED OPERATING CONDITIONS

Symbol	Rating	Min	Max	Unit	
V <sub>DD</sub>	Power Supply Voltage – Input Side		3.0	5.0	V
V <sub>CCA</sub> , V <sub>CCB</sub>	Power Supply Voltage – Driver Side 8–V UVLO Version		9.5	30	V
		18.5	30	V	
V <sub>IN</sub>	Logic Input Voltage at Pins INA, INB, and AN	IB	0	18	V
V <sub>ENA/DIS</sub>	Logic Input Voltage at Pin ENA/DIS		0	5.0	V
T <sub>A</sub>	Ambient Temperature	-40	+125	°C	
TJ	Junction Temperature	Junction Temperature			°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

#### THERMAL CHARACTERISTICS

Symbol	Rating	Condition	Value	Unit
$R_{ heta JA}$	Thermal Characteristics, (Note 13) Thermal Resistance Junction–Air 16–SOIC–WB	100 mm <sup>2</sup> , 1 oz Copper, 1 Surface Layer (1S0P) 100 mm <sup>2</sup> , 2 oz Copper, 1 Surface Layer (1S0P)	120 81	°C/W
$R_{\theta JC}$	Thermal Resistance Junction–Case	100 mm <sup>2</sup> , 1 oz Copper, 1 Surface Layer (1S0P)	38	°C/W
$\Psi_{JT}$	Thermal Resistance Junction-to-Top		18	°C/W
$\Psi_{JB}$	Thermal Resistance Junction-to-Board		55	°C/W
P <sub>D</sub>	Power Dissipation (Note 13) 16–SOIC–WB	100 mm <sup>2</sup> , 1 oz Copper, 1 Surface Layer (1S0P) 100 mm <sup>2</sup> , 2 oz Copper, 1 Surface Layer (1S0P)	0.8 1.5	W

<sup>12.</sup> Refer to ELECTRICAL CHARACTERISTICS, RECOMMENDED OPERATING RANGES and/or APPLICATION INFORMATION for Safe Operating parameters.

#### **ISOLATION CHARACTERISTICS**

Symbol	Parameter	Condition	Min	Тур	Max	Unit
VISO,INPUT TO OUTPUT	Input to Output Isolation Voltage	$T_A = 25$ °C, Relative Humidity < 50%, t = 1.0 minute, $I_{I-O}$ 10 A, 50 Hz	5000			$V_{RMS}$
V <sub>ISO,OUTA</sub> TO OUTB	OUTA to OUTB Isolation Voltage	(Notes 14, 15, 16)	1500			V <sub>RMS</sub>
R <sub>ISO</sub>	Isolation Resistance	V <sub>I_O</sub> = 500 V (Note 14)	10 <sup>11</sup>			Ω

<sup>14.</sup> Device is considered a two - terminal device: pins 1 to 8 are shorted together and pins 9 to 16 are shorted together.

<sup>13.</sup> JEDEC standard: JESD51-2, and JESD51-3.

 <sup>15.5,000</sup> V<sub>RMS</sub> for 1 – minute duration is equivalent to 6,000 V<sub>RMS</sub> for 1 – second duration.
 16. The input – output isolation voltage is a dielectric voltage rating per UL1577. It should not be regarded as an input – output continuous voltage rating. For the continuous working voltage rating, refer to equipment – level safety specification or DIN VDE V 0884 – 11 Safety and Insulation Ratings Table

**ELECTRICAL CHARACTERISTICS** ( $V_{DD} = 5 \text{ V}, V_{CCA} = V_{CCB} = 12 \text{ V}, \text{ or } 20 \text{ V} \text{ (Note 18) and VSSA} = \text{VSSB, for typical values } T_J = T_A = 25^{\circ}\text{C}, \text{ for min/max values } T_J = -40^{\circ}\text{C to } +125^{\circ}\text{C}, \text{ unless otherwise specified. (Note 17))}$ 

Symbol	Parameter	Condition	Min	Тур	Max	Unit
		Jonation	.41111	אני ן	1	J
	WER SUPPLY SECTION (V <sub>DD</sub> )	ly y oyy y	000	700	1000	_
IQVDD	V <sub>DD</sub> Quiescent Current	$V_{INA} = V_{INB} = 0 \text{ V}, V_{ENABLE} = V_{DD}$ or $V_{DISABLE} = 0 \text{ V}$	600	730	1000	μΑ
		$V_{INA} = V_{INB} = 5 \text{ V}, V_{ENABLE} = 0 \text{ V}$ or $V_{DISABLE} = 0 \text{ V}$	600	760	1000	μΑ
		$V_{INA} = V_{INB} = 5 \text{ V}, V_{ENABLE} = V_{DD}$ or $V_{DISABLE} = 0 \text{ V}$	7.0	9.5	11	mA
I <sub>VDD</sub>	V <sub>DD</sub> Operating Current	$f_{\text{IN}}$ = 500 kHz, 50% duty cycle, $C_{\text{OUT}}$ = 100 pF	5.0	6.0	8.0	mA
V <sub>DDUV+</sub>	V <sub>DD</sub> Supply Under–Voltage Positive–Going Threshold	V <sub>DD</sub> = Sweep	2.7	2.8	2.9	V
V <sub>DDUV</sub> _	V <sub>DD</sub> Supply Under–Voltage Negative–Going Threshold	V <sub>DD</sub> = Sweep	2.6	2.7	2.8	V
V <sub>DDHYS</sub>	V <sub>DD</sub> Supply Under-Voltage Lockout Hysteresis	V <sub>DD</sub> = Sweep	_	0.1	_	V
	POWER SUPPLY SECTION (VCCA AND VCCB	3)				
IQVCCA IQVCCB	V <sub>CCA</sub> and V <sub>CCB</sub> Quiescent Current	$V_{INA} = V_{INB} = 0 \text{ V},$ $V_{CCA} = V_{CCB} = 12 \text{ V}, \text{ per channel}$	200	280	400	μΑ
		V <sub>INA</sub> = V <sub>INB</sub> = 5 V, V <sub>CCA</sub> = V <sub>CCB</sub> = 12 V, per channel	300	380	500	μΑ
I <sub>VCCA</sub> I <sub>VCCB</sub>	V <sub>CCA</sub> and V <sub>CCB</sub> Operating Current	Current per channel (f <sub>IN</sub> = 500 kHz, 50% duty cycle), V <sub>CCA</sub> = V <sub>CCB</sub> = 12 V, C <sub>OUT</sub> = 100 pF	2.0	3.0	4.0	mA
VCCA and VC	CCB UVLO THRESHOLD (8-V UVLO VERSION)					
V <sub>CCAUV+</sub> V <sub>CCBUV+</sub>	V <sub>CCA</sub> and V <sub>CCB</sub> Supply Under–Voltage Positive–Going Threshold		8.3	8.7	9.2	V
V <sub>CCAUV</sub> -	V <sub>CCA</sub> and V <sub>CCB</sub> Supply Under–Voltage Negative–Going Threshold		7.8	8.2	8.7	V
V <sub>CCHYS</sub>	Under-Voltage Lockout Hysteresis		_	0.5	_	V
t <sub>UVFLT</sub>	Under-Voltage Debounce Time		_	_	10	μs
VCCA and VC	CCB UVLO THRESHOLD (17-V UVLO VERSION	l)				
V <sub>CCAUV+</sub> V <sub>CCBUV+</sub>	V <sub>CCA</sub> and V <sub>CCB</sub> Supply Under–Voltage Positive–Going Threshold		16	17	18	V
V <sub>CCAUV</sub> -	V <sub>CCA</sub> and V <sub>CCB</sub> Supply Under–Voltage Negative–Going Threshold		15	16	17	V
V <sub>CCHYS</sub>	Under-Voltage Lockout Hysteresis		_	1	-	V
t <sub>UVFLT</sub>	Under-Voltage Debounce Time		_	_	10	μs
	SECTION (INA, INB, AND ANB)					
V <sub>INH</sub>	High Level Input Voltage		1.4	1.6	1.8	V
V <sub>INL</sub>	Low Level Input Voltage		0.9	1.1	1.3	V
V <sub>INHYS</sub>	Input Logic Hysteresis		_	0.5	_	V
I <sub>IN+</sub>	High Level Logic Input Bias Current	V <sub>IN</sub> = 5 V	20	25	33	μΑ
I <sub>IN</sub> _	Low Level Logic Input Bias Current	V <sub>IN</sub> = 0 V	_	_	1.0	μΑ
LOGIC INPUT	SECTION (for ENABLE Version only)					
V <sub>ENAH</sub>	Enable High Voltage		1.4	1.6	1.8	V
V <sub>ENAL</sub>	Enable Low Voltage		0.9	1.1	1.3	V
V <sub>ENAHYS</sub>	Enable Logic Hysteresis		-	0.5	_	V
LOGIC INPUT	SECTION (for DISABLE Version only)					
V <sub>DISH</sub>	Disable High Voltage		1.4	1.6	1.8	V
V <sub>DISL</sub>	Disable Low Voltage		0.9	1.1	1.3	V
V <sub>DISHYS</sub>	Disable Logic Hysteresis		_	0.5	_	V

**ELECTRICAL CHARACTERISTICS** ( $V_{DD} = 5 \text{ V}, V_{CCA} = V_{CCB} = 12 \text{ V}, \text{ or } 20 \text{ V} \text{ (Note 18) and VSSA} = \text{VSSB, for typical values } T_J = T_A = 25^{\circ}\text{C}, \text{ for min/max values } T_J = -40^{\circ}\text{C to } +125^{\circ}\text{C}, \text{ unless otherwise specified. (Note 17)) (continued)}$ 

Symbol	Parameter	Condition	Min	Тур	Max	Unit
DEAD-TIME A	AND OVERLAP SECTION					
t <sub>DT,MIN</sub>	Minimum Dead-Time	DT pin is left open	0	10	23	ns
t <sub>DT</sub>	Dead-Time	R <sub>DT</sub> = 20 kΩ	155	200	245	ns
		R <sub>DT</sub> = 100 kΩ	800	1000	1200	ns
$\Delta t_{DT}$	Dead-Time Mismatch between OUTB → OUTA	$R_{DT} = 20 \text{ k}\Omega$	-30	-	30	ns
	and OUTA → OUTB	$R_{DT} = 100 \text{ k}\Omega$	-150	-	150	ns
$V_{DT,OLE}$	OUTA & OUTB Overlap Allow	DT pin Pulled to VDD	-	4.5	5.0	V
GATE DRIVE	SECTION					
I <sub>OUTA+,</sub> I <sub>OUTB+</sub>	OUTA and OUTB Source Peak Current (Note 19)	$\begin{split} V_{INA} &= V_{INB} = 5 \text{ V, PW} \leq 5  \mu\text{s,} \\ V_{CCA} &= V_{CCB} =  12 \text{ V} \end{split}$	2.6	4.5	_	Α
I <sub>OUTA-,</sub> I <sub>OUTB-</sub>	OUTA and OUTB Sink Peak Current (Note 19)	$\begin{aligned} V_{INA} &= V_{INB} = 5 \text{ V, PW} \leq 5  \mu\text{s} \\ V_{CCA} &= V_{CCB} = 12 \text{ V} \end{aligned}$	7.0	9.0	-	Α
V <sub>OHA</sub> , V <sub>OHB</sub>	High Level Output Voltage (V <sub>CC</sub> – V <sub>OUT</sub> )	I <sub>OUT</sub> = 100 mA	-	-	250	mV
$V_{OLA,} V_{OLB}$	Low Level Output Voltage (V <sub>OUT</sub> – V <sub>SS</sub> )	I <sub>OUT</sub> = 100 mA	-	_	100	mV
DYNAMIC ELI	ECTRICAL CHARACTERISTICS					
t <sub>PDON</sub>	Turn-On Propagation Delay from INx to OUTx	$V_{CCA} = V_{CCB} = 12 \text{ V}, C_{LOAD} = 0 \text{ nF}$	23	36	49	ns
		V <sub>CCA</sub> = V <sub>CCB</sub> = 20 V, C <sub>LOAD</sub> = 0 nF	26	39	52	ns
t <sub>PDOFF</sub>	Turn-Off Propagation Delay from INx to OUTx	$V_{CCA} = V_{CCB} = 12 \text{ V}, C_{LOAD} = 0 \text{ nF}$	23	36	49	ns
		$V_{CCA} = V_{CCB} = 20 \text{ V}, C_{LOAD} = 0 \text{ nF}$	26	39	52	ns
t <sub>PWD</sub>	Pulse Width Distortion (t <sub>PDON</sub> - t <sub>PDOFF</sub> )		-8	-	8	ns
t <sub>DM</sub>	Propagation Delay Mismatching between Channels	INA and INB shorted, f <sub>IN</sub> = 100 kHz	-8	_	8	ns
t <sub>R</sub>	Turn-On Rise Time	C <sub>LOAD</sub> = 1.8 nF	_	9	15	ns
t <sub>F</sub>	Turn-Off Fall Time		-	8	15	ns
T <sub>ENABLE,OUT,</sub> T <sub>DISABLE,OUT</sub>	ENABLE or DISABLE to OUTx Turn-On/Off Propagation Delay	V <sub>CCA</sub> = V <sub>CCB</sub> = 12 V	23	36	49	ns
· DISABLE,OUT	Tropagation 25tay	V <sub>CCA</sub> = V <sub>CCB</sub> = 20 V	26	39	52	ns
t <sub>PW</sub>	Minimum Input Pulse Width that Change Output State	C <sub>LOAD</sub> = 0 nF	-	15	23	ns
T <sub>FLT,ANB</sub>	Glitch Filter on the ANB Pin		2.4	3.3	4.2	μS
CMTI	Common Mode Transient Immunity	Slew rate of GND versus VSSA and VSSB. INA and INB both are tied to V <sub>DD</sub> or GND. V <sub>CM</sub> = 1500 V	200	_	_	V/ns

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

<sup>17.</sup> Performance guaranteed over the indicated operating temperature range by design and/or characterization tested at  $T_J = T_A = 25^{\circ}C$ . 18.  $V_{CCA} = V_{CCB} = 12$  V is used for the test condition of 5–V and 8–V UVLO,  $V_{CCA} = V_{CCB} = 20$  V is used for 17–V UVLO.

<sup>19.</sup> These parameters verified by bench test only and not tested in production.

#### **INSULATION CHARACTERISTICS CURVES**

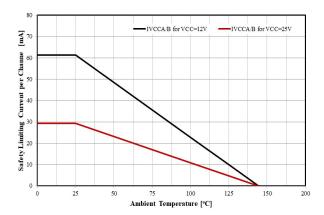


Figure 4. Thermal Derating Curve for Safety-related Limiting Current (Current in Each Channel with Both Channels Running Simultaneously)

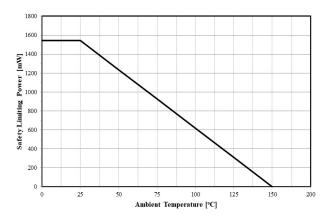


Figure 5. Thermal Derating Curve for Safety-related Limiting Power

#### TYPICAL CHARACTERISTIC

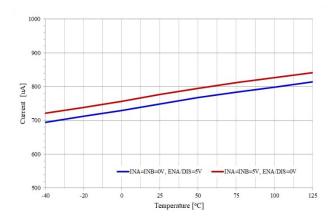


Figure 6. Quiescent  $V_{DD}$  Supply Current vs. Temperature ( $V_{DD}$  = 5 V, INA = INB = 0 V or 5 V, ENA/DIS = 5 V and No Load)

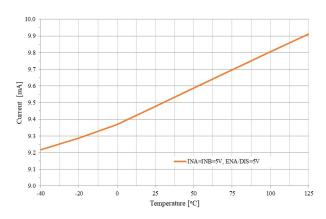


Figure 7. Quiescent  $V_{DD}$  Supply Current vs. Temperature ( $V_{DD} = 5 \text{ V}$ , INA = INB = ENA/DIS = 5 V and No Load)

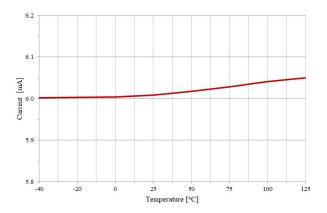


Figure 8. V<sub>DD</sub> Operating Current vs. Temperature (V<sub>DD</sub> = 5 V, No Load, and Switching Frequency = 500 kHz)

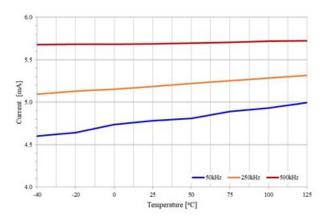


Figure 9. V<sub>DD</sub> Operating Current vs. Temperature (V<sub>DD</sub> = 5 V, No Load, and Different Switching Frequency)

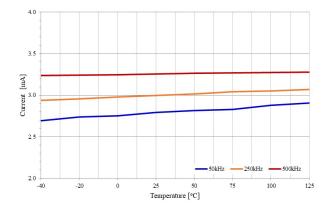


Figure 10. Per Channel  $V_{DD}$  Operating Current vs. Temperature ( $V_{DD}$  = 5 V, No Load, and Different Switching Frequency

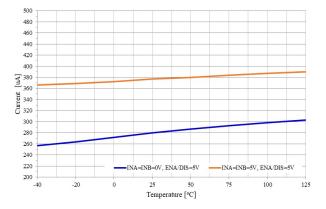


Figure 11. Per Channel Quiescent  $V_{CC}$  Supply Current vs. Temperature (INA = INB = 0 V or 5 V, ENA/DIS = 5 V and No Load

#### TYPICAL CHARACTERISTIC (Continued)

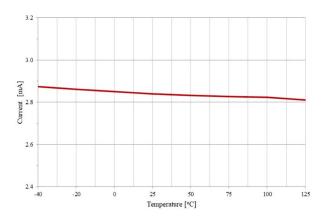


Figure 12. Per Channel V<sub>CC</sub> Operating Current vs. Temperature (No Load and Switching Frequency = 500 kHz

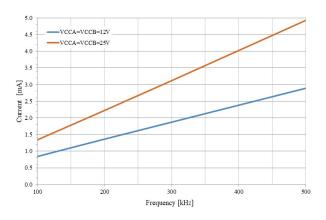


Figure 13. Per Channel Operating Current vs. Frequency (No Load,  $V_{CCA} = V_{CCB} = 12 \text{ V}$ , or 25 V)

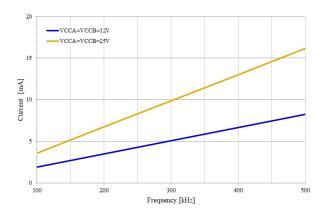


Figure 14. Per Channel Operating Current vs. Frequency ( $C_{LOAD} = 1 \text{ nF}, V_{CCA} = V_{CCB} = 12 \text{ V},$  or 25 V)

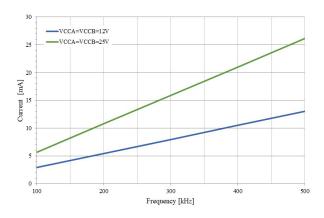


Figure 15. Per Channel Operating Current vs. Frequency ( $C_{LOAD}$  = 1.8 nF,  $V_{CCA}$  =  $V_{CCB}$  = 12 V, or 25 V)

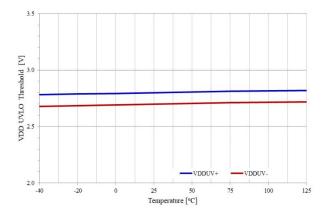


Figure 16.  $V_{DD}$  UVLO Threshold vs. Temperature

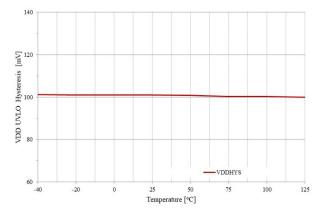
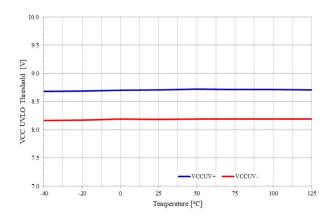


Figure 17. V<sub>DD</sub> UVLO Hysteresis vs. Temperature

#### TYPICAL CHARACTERISTIC (Continued)



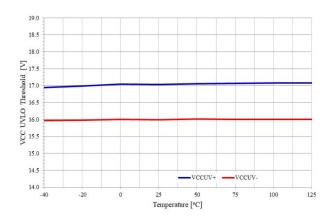
ON 550 VCCHYS

450 -40 -20 0 25 50 75 100 125

Temperature [°C]

Figure 18. V<sub>CC</sub> 8–V UVLO Threshold vs. Temperature

Figure 19. V<sub>CC</sub> 8–V UVLO Hysteresis vs. Temperature



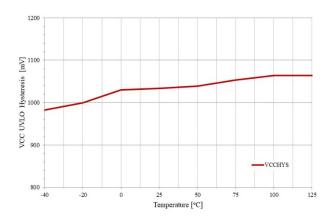
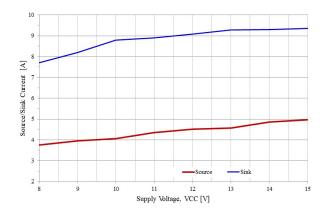


Figure 20.  $V_{CC}$  17-V UVLO Threshold vs. Temperature

Figure 21.  $V_{CC}$  17-V UVLO Hysteresis vs. Temperature





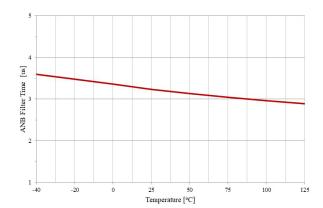


Figure 23. ANB Filer Time vs. Temperature

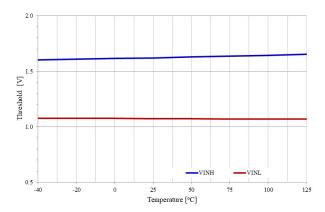


Figure 24. Input Logic Threshold vs. Temperature (INA, INB, and ANB)

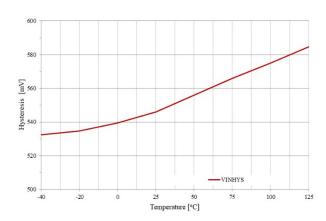


Figure 25. Input Logic Hysteresis vs. Temperature (INA, INB, and ANB)

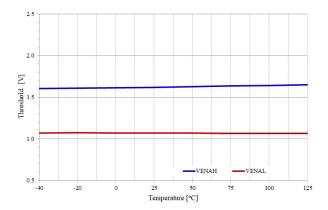


Figure 26. ENA/DIS Threshold vs. Temperature (ENABLE, and DISABLE)

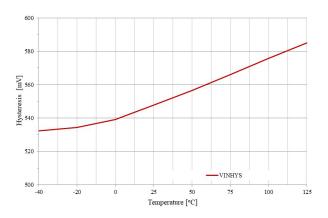


Figure 27. ENA/DIS Hysteresis vs. Temperature (ENABLE, and DISABLE)

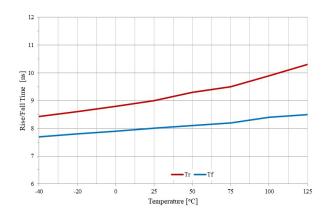


Figure 28. Rise/Fall Time vs. Temperature  $(C_{LOAD} = 1.8 \text{ nF})$ 

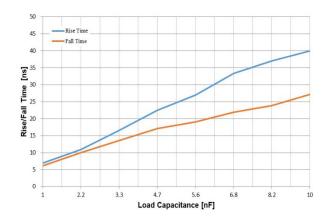


Figure 29. Rise/Fall Time vs. Temperature (V<sub>CC</sub> = 12 V, and Different Load)

### TYPICAL CHARACTERISTIC (Continued)

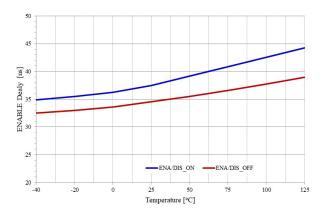


Figure 30. ENA/DIS Delay Time vs. Temperature

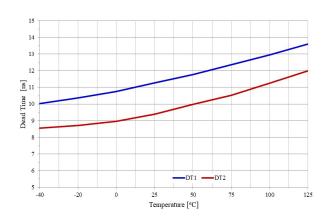


Figure 31. Dead Time vs. Temperature  $(R_{DT} = Open)$ 

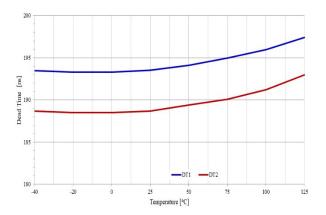


Figure 32. Dead Time vs. Temperature ( $R_{DT} = 20k\Omega$ )

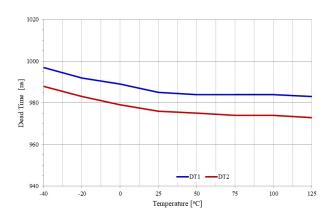


Figure 33. Dead Time vs. Temperature (R  $_{DT}$  = 100 k $\Omega$ )

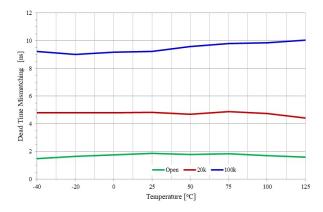


Figure 34. Dead Time Mismatching vs. Temperature

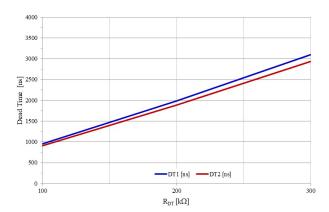


Figure 35. Dead Time vs.  $R_{\rm DT}$ 

#### TYPICAL CHARACTERISTIC (Continued)

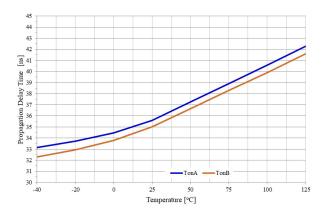


Figure 36. Turn-on Propagation Delay vs.
Temperature

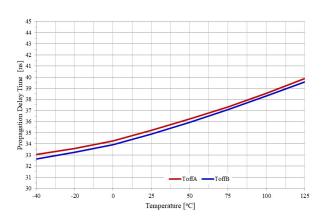


Figure 37. Turn-off Propagation Delay vs. Temperature

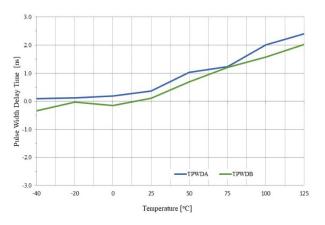


Figure 38. Pulse Width Distortion vs. Temperature

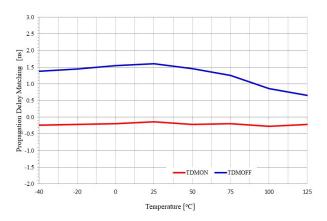


Figure 39. Propagation Delay Matching vs. Temperature

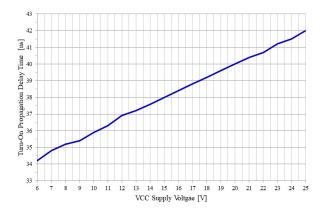


Figure 40. Turn-on Propagation Delay vs. V<sub>CC</sub> Supply Voltage

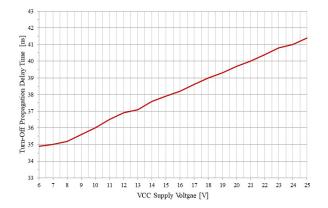


Figure 41. Turn-off Propagation Delay vs. V<sub>CC</sub> Supply Voltage

#### PARAMETER MEASUREMENT DEFINITION

#### **Switching Time Definitions**

Figure 42 shows the switching time definitions of the turn–on  $(t_{PDON})$  and turn–off  $(t_{PDOFF})$  propagation delay time among the driver's two input signals INA, INB and two

output signals OUTA, OUTB. The typical values of the propagation delay (t<sub>PDON</sub>, T<sub>PDOFF</sub>), pulse width distortion (t<sub>PWD</sub>) and delay matching between channels times are specified in the electrical characteristics table.

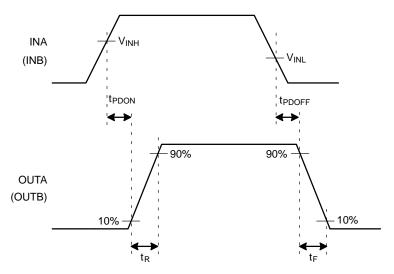


Figure 42. Switching Time Definitions

#### **Enable and Disable Function**

Figure 43 shows the response time according to an ENABLE or the DISABLE operating modes. If the ENA/DIS pin voltage goes to LOW state, i.e.  $V_{ENA} \leq 1.1~V$  shuts down both outputs simultaneously and Pull the ENA/DIS pin HIGH (or left open), i.e.  $V_{ENA} \geq 1.6~V$  to

operate normally in an ENABLE mode as shown in Figure 43 (a). Conversely, if the ENA/DIS pin voltage goes to HIGH state, i.e.  $V_{DIS} \ge 1.6 \text{ V}$  shuts down both outputs simultaneously and Pull the ENA/DIS pin LOW (or left open), i.e.  $V_{DIS} \le 1.1 \text{ V}$  operate normally in the DISABLE mode as shown in Figure 43 (b).

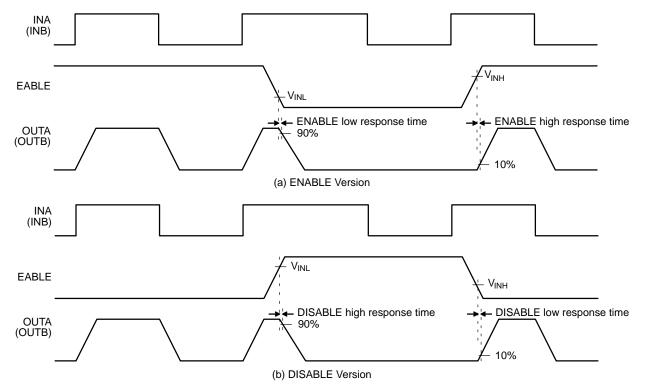


Figure 43. Timing Chart of Enable Function

#### Programmable Dead-Time

Dead time is automatically inserted whenever the dead time of the external two input signals (between INA and INB signals) is shorter than internal setting dead times (DT1 and DT2). Otherwise, if the external input signal dead times are larger than internal dead–time, the dead time is not modified by the gate driver and internal dead–time definition as shown in Figure 44.

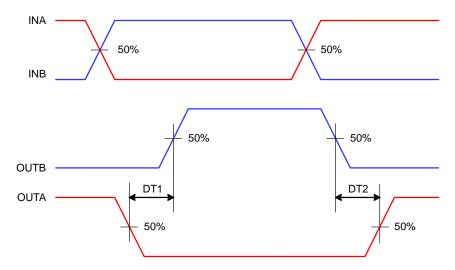


Figure 44. Internal Dead-Time Definitions

Figure 45 shows the definition of internal dead time and shoot–through prevention when input signals applied at same time.

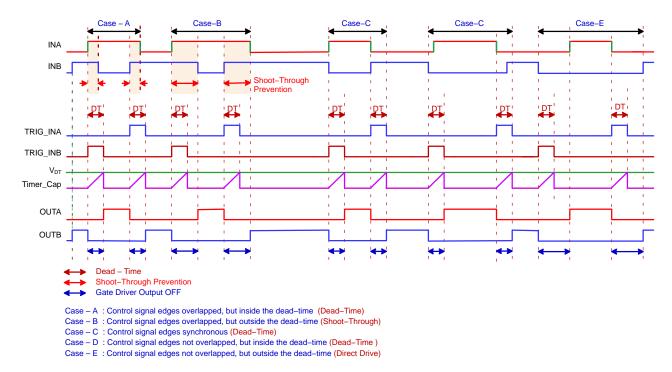


Figure 45. Internal Dead-Time Definitions

#### **DEVICE INFORMATION**

#### **Input to Output Operation Definitions**

The NCP51561 provides important protection functions such as independent under-voltage lockout for both gate driver; enable or disable function and dead-time control function. Figure 46 shows an overall input to output timing diagram when shutdown mode via ENA/DIS pin in the

*CASE–A*, and Under–Voltage Lockout protection on the primary– and secondary–sides power supplies events in the *CASE–B*. The gate driver output (OUTA and OUTB) were turn–off when cross–conduction event at the dead time control mode in the *CASE–C*.

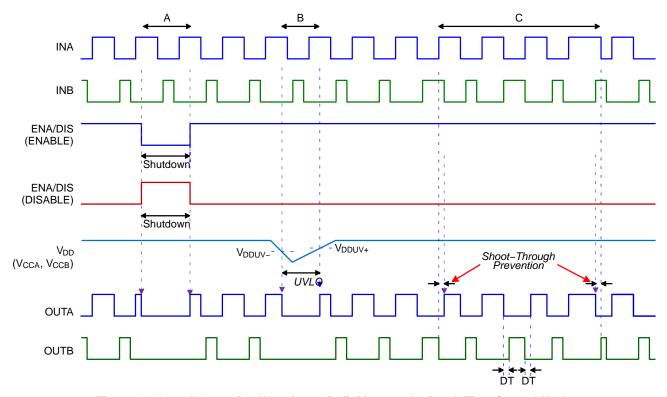


Figure 46. Overall Operating Waveforms Definitions at the Dead-Time Control Mode

#### Input and Output Logic Table

Table 1 shows an input to output logic table according to the dead time control modes and an enable or the disable operation mode.

**Table 1. INPUT AND OUTPUT LOGIC TABLE** 

	INPUT			OUT	PUT	
		ENA	/DIS			
INA	INB	ENABLE	DISABLE	OUTA	OUTB	NOTE
L	L	H or Left open	L or Left open	L	L	Programmable dead time control with R <sub>DT</sub> .
L	Н	H or Left open	L or Left open	L	Н	
Н	L	H or Left open	L or Left open	Н	L	
Н	Н	H or Left open	L or Left open	L	L	DT pin is left open Or programmed with R <sub>DT</sub> .
Н	Н	H or Left open	L or Left open	Н	Н	DT pin pulled to V <sub>DD</sub> .
Left open	Left open	H or Left open	L or Left open	L	L	
Х	Х	L	Н	L	L	

20. "X" means L, H or left open.

#### **Input Signal Configuration**

The NCP51561 allows to set the input signal configuration through the ANB pin for user convenience. There are four operating modes that allow to change the configuration of the input to output channels (e.g. single input – dual output, or dual input – dual output), and select

the shutdown function (e.g. Disable or Enable mode) as below Table 2. Unused input pins (e.g. INA, INB, and ANB) should be tied to GND to achieve better noise immunity. In addition, the ANB pin has an internal filter time typically 3.3 µs to achieve the noise immunity.

Table 2. INPUT SIGNAL CONFIGURATION LOGIC TABLE

	Functional Input Pin				
Mode	INA	INB	ANB	ENA/DIS	Input Configuration
1	INA	INB	L	DISABLE	Dual-Input, Dual-Output with disable mode (ENA/DIS = LOW)
2	INA	Х	Н	DISABLE	Single-Input (INA), Dual-Output with disable mode(ENA/DIS = LOW)
3	INA	INB	L	ENABLE	Dual-Input, Dual-Output with enable mode (ENA/DIS = HIGH)
4	INA	Х	Н	ENABLE	Single–Input (INA), Dual–Output with enable mode (ENA/DISE = HIGH)

Figure 47 shows an operating timing chart of input to output and shutdown function according to the ANB and ENA/DIS pins. The ENA/DIS and ANB pins are only functional when  $V_{DD}$  stays above the specified UVLO threshold. It is recommended to tie these pins to Ground if the ENA/DIS and ANB pins are not used to achieve better noise immunity, and it is recommended to bypass using a 1 nF low ESR/ESL capacitor close to these pins for the

DISABLE (e.g. NCP51561xB) mode. When it is not possible to connect ANB to GND then external pull–down resistor few ten  $k\Omega$  (e.g. 10 ~47  $k\Omega$ ) is recommended to prevent unwanted ANB activation by external interference as despite its internal 3.3  $\mu$ s filter.

The OUTA and OUTB works as complementary outputs from PWM input signal on the INA pin regardless the INB signal when the ANB pin is HIGH.

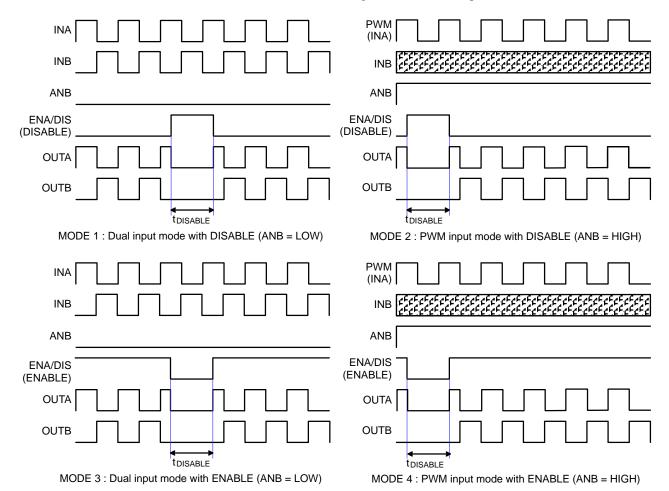


Figure 47. Timing Chart of ENABLE and DISABLE Modes

#### PROTECTION FUNCTION

The NCP51561 provides the protection features include enable function, Cross Conduction Protection, and Under–Voltage Lockout (UVLO) of power supplies on primary–side ( $V_{DD}$ ), and secondary–side both channels ( $V_{CCA}$ , and  $V_{CCB}$ ).

#### Under-Voltage Lockout Protection V<sub>DD</sub> and V<sub>CCx</sub>

The NCP51561 provides the Under–Voltage Lockout (UVLO) protection function for  $V_{DD}$  in primary–side and both gate drive output for  $V_{CCA}$  and  $V_{CCB}$  in secondary–side as shown in Figure 48.

The gate driver is running when the  $V_{DD}$  supply voltage is greater than the specified under–voltage lockout threshold voltage (e.g. typically 2.8 V) and ENA/DIS pin is HIGH or LOW states for an ENABLE (e.g. NCP51561xA) or the DISABLE (e.g. NCP51561xB) mode respectively.

In addition, both gate output drivers have independent under voltage lockout protection (UVLO) function and each channel supply voltages in secondary–side (e.g.  $V_{CCA}$ , and  $V_{CCB}$ ) need to be greater than specified UVLO threshold level in secondary–side to let the output operate per input signal. The typical  $V_{CCx}$  UVLO threshold voltage levels for each option are per below Table 3.

Table 3. V<sub>CCx</sub> UVLO OPTION TABLE

Option	V <sub>CC</sub> UVLO Level	Unit
8–V	8.7	V
17–V	17	V

UVLO protection has an hysteresis to provide immunity to short  $V_{CC}$  drops that can occur.

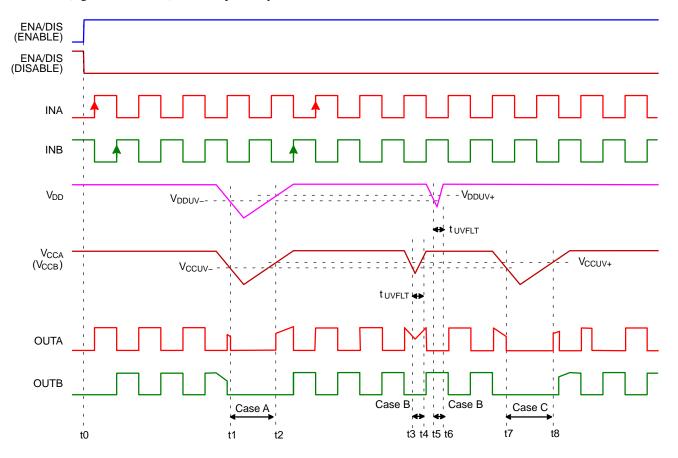


Figure 48. Timing Chart Under-Voltage Lockout Protection

#### Cross-Conduction Prevention and Allowed Overlapped Operation

The cross conduction prevents both high– and low–side switches from conducting at the same time when the dead time (DT) control mode is in half–bridge type, as shown in Figure 49.

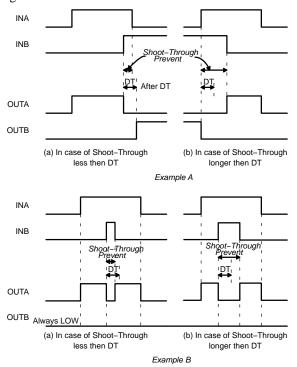


Figure 49. Concept of Shoot-Through Prevention

#### **Programmable Dead Time Control**

Cross–conduction between both driver outputs (OUTA, and OUTB) is not allowed with minimum dead time ( $t_{DTMIN}$ ) typically 10 ns when the DT pin is open in the MODE–A. External resistance ( $R_{DT}$ ) controls dead time when the DT pin resistor between 1 k $\Omega$  and 300 k $\Omega$  in the

For full topologies flexibility, cross conduction can be allowed both high– and low–side switches conduct at the same time when the DT pin is pulled to  $V_{DD}$  for example, as shown in Figure 50.

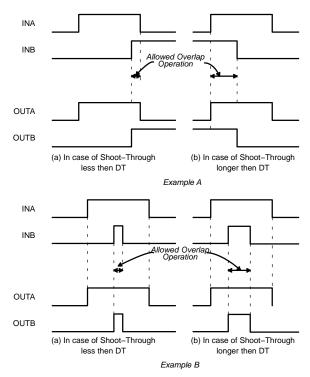


Figure 50. Concept of Allowed the Shoot-Through

**MODE–B**. Overlap is not allowed when the dead time (DT) control mode is activated.

The dead time (DT) between both outputs is set according to: DT (in ns) =  $10 \times R_{DT}$  (in k $\Omega$ ).

Overlap is allowed for both outputs when the DT pin is pulled to VDD in the **MODE–C**, as shown in Figure 51.

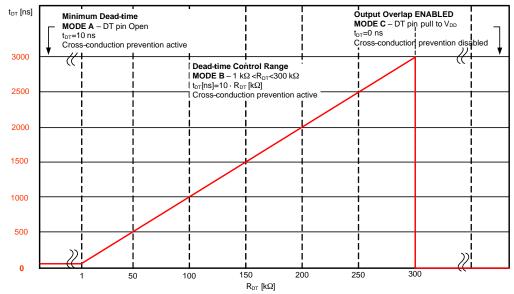


Figure 51. Timing Chart of Dead-Time Mode Control

#### **Common Mode Transient Immunity Testing**

Figure 52 is a simplified diagram of the Common Mode Transient Immunity (CMTI) testing configuration.

CMTI is the maximum sustainable common—mode voltage slew rate while maintaining the correct output.

CMTI applies to both rising and falling common—mode voltage edges. CMTI is tested with the transient generator connected between GND and VSSA and VSSB. ( $V_{CM}\!=\!1500~V$ )

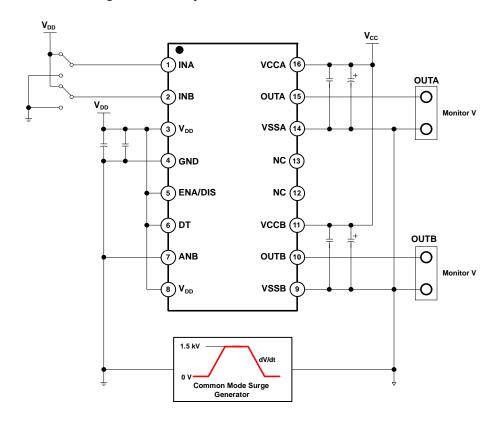


Figure 52. Common Mode Transient Immunity Test Circuit

#### APPLICATION INFORMATION

This section provides application guidelines when using the NCP51561.

#### **Power Supply Recommendations**

It is important to remember that during the Turn–On of switch the output current to the Gate is drawn from the  $V_{CCA}$  and  $V_{CCB}$  supply pins. The  $V_{CCA}$  and  $V_{CCB}$  pins should be bypassed with a capacitor with a value of at least ten times the Gate capacitance, and no less than 100 nF and located as close to the device as possible for the purpose of decoupling. A low ESR, ceramic surface mount capacitor is necessary. We recommend using 2 capacitors; a 100 nF ceramic surface—mount capacitor which can be very close to the pins of the device, and another surface—mount capacitor of few microfarads added in parallel.

#### **Input Stage**

The input signal pins (INA, INB, ANB, and ENA/DIS) of the NCP51561 are based on the TTL compatible input-threshold logic that is independent of the V<sub>DD</sub> supply voltage. The logic level compatible input provides a typically high and low threshold of 1.6 V and 1.1 V respectively. The input signal pins impedance of the NCP51561 is 200 k $\Omega$  typically and the INA, INB, and ANB pins are pulled to GND pin and ENA/DIS pin pulled to V<sub>DD</sub> pin for an ENABLE mode as shown in Figure 53. Conversely, ENA/DIS pin pulled to GND pin for the DISABLE version. It is recommended that ENA/DIS pin should be tie to VDD or GND pins for ENABLE and DISABLE versions respectively if the ENA/DIS pin is not used to achieve better noise immunity because the ENA/DIS pin is quite responsive, as far as propagation delay and other switching parameters are concerned.

An RC filter is recommended to be added on the input signal pins to reduce the impact of system noise and ground bounce, the time constant of the RC filter. Such a filter should use an  $R_{IN}$  in the range of 0  $\Omega$  to 100  $\Omega$  and a  $C_{IN}$  between 10 pF and 100 pF. In the example, an  $R_{IN}=51~\Omega$  and a  $C_{IN}=33$  pF are selected, with a corner frequency of approximately 100 MHz. When selecting these components, it is important to pay attention to the trade–off between good noise immunity and propagation delay.

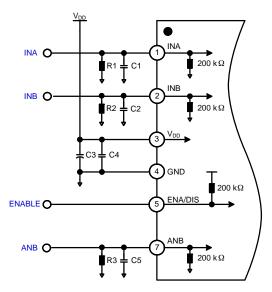


Figure 53. Schematic of Input Stage

#### **Output Stage**

The output driver stage of the NCP51561 features a pull up structure and a pull down structure.

The pull up structure of the NCP51561 consists of a PMOS stage ensuring to pull all the way to the  $V_{CC}$  rail. The pull down structure of the NCP51561 consists of a NMOS device as shown in Figure 54.

The output impedance of the pull up and pull down switches shall be able to provide about +4.5 A and -9 A peak currents typical at  $25^{\circ}$ C and the minimum sink and source peak currents at  $-40^{\circ}$ C are -7 A sink and +2.6 A source.

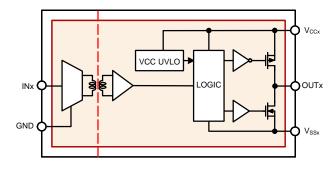


Figure 54. Schematic of Output Stage

#### **Consideration of Driving Current Capability**

Peak source and sink currents ( $I_{SOURCE}$ , and  $I_{SINK}$ ) capability should be larger than average current ( $I_{G, AV}$ ) as shown in Figure 55.

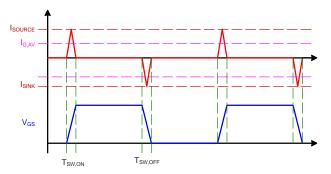


Figure 55. Definition of Current Driving Capability

The approximate maximum gate charge  $Q_G$  that can be switched in the indicated time for each driver current rating may be calculate: Needed driver current ratings depend on what gate charge  $Q_G$  must be moved in what switching time  $t_{SW-ON/OFF}$  because average gate current during switching is  $I_G$ .

$$I_{\text{G.AV}} = \frac{Q_{\text{G}}}{t_{\text{SW,ON/OFF}}} \tag{eq. 1}$$

The approximate gate driver source and sink peak currents can be calculated as below equations

At turn-on (Sourcing current)

$$I_{SOURCE} \ge 1.5 \times \frac{Q_{G}}{t_{SW,ON}}$$
 (eq. 2)

At turn-off (Sinking current)

$$I_{SINK} \ge 1.5 \times \frac{Q_G}{t_{SWOFF}}$$
 (eq. 3)

where,

 $Q_G$  = Gate charge at  $V_{GS}$  =  $V_{CC}$ t<sub>SW, ON/OFF</sub> = Switch On / Off time 1.5 = empirically determined factor

(Influenced by I<sub>G,AV</sub> vs. I<sub>DRV</sub>, and circuit parasitic)

#### **Consideration of Gate Resistor**

The gate resistor is also sized to reduce ringing voltage by parasitic inductances and capacitances. However, it limits the current capability of the gate driver output. The limited current capability value induced by turn—on and off gate resistors can be obtained with below equation.

$$I_{SOURCE} = \frac{V_{CC} - V_{OH}}{R_{G,ON}}$$

$$I_{SINK} = \frac{V_{CC} - V_{OL}}{R_{G,OFF}}$$
 (eq. 4)

where:

I<sub>SOURCE</sub>: Source peak current I<sub>SINK</sub>: Sink peak current.

V<sub>OH</sub>: High level output voltage drop V<sub>OL</sub>: Low level output voltage drop

#### **Application Circuits with Output Stage Negative Bias**

SiC MOSFET unique operating characteristics need to be carefully considered to fully benefits from SiC characteristics. The gate driver needs to be capable of providing +20 V and -2 V to -5 V negative bias with minimum output impedance and high current capability.

When parasitic inductances are introduced by non-ideal PCB layout and long package leads (e.g. TO-220 and TO-247 type packages), there could be ringing in the gate-source drive voltage of the power transistor during high di/dt and dv/dt switching. If the ringing is over the threshold voltage, there is the risk of unintended turn-on and even shoot-through. Applying a negative bias on the gate drive is a popular way to keep such ringing below the threshold. Negative voltage can improve the noise tolerance of SiC MOSFET to suppress turning it unintentionally. The negative gate—source voltage makes the capacitance of Cgd becoming lower, which can reduce the ringing voltage.

Below are a few examples of implementing negative gate drive bias. The first example with negative bias with two isolated—bias power supplies as shown in Figure 56. Power supply VHx determines the positive drive output voltage and VLx determines the negative turn—off voltage for each channels. This solution requires more power supplies than the conventional bootstrapped power supply example; however, it provides more flexibility when setting the positive, VHx, and negative, VLx, rail voltages.

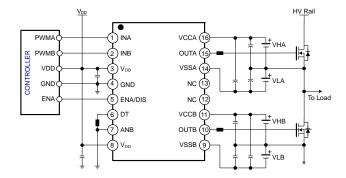


Figure 56. Negative Bias with Two Isolated-Bias Power Supplies

Figure 57 shows another example with negative bias turn—off on the gate driver using a Zener diode on an isolated power supply. The negative bias set by the voltage of Zener diode. For example, if the isolated power supply, VHx for

each channels, the turn-off voltage will be -5.1 V and turn-on voltage will be 20 V -5.1 V  $\approx 15$  V.

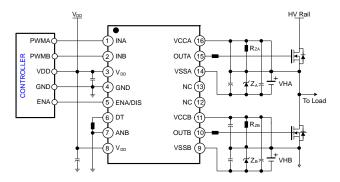


Figure 57. Negative Bias with Zener Diode on Single Isolated-Bias Power Supply

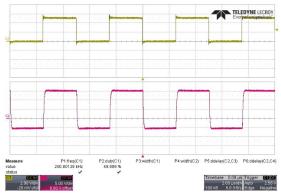
Moreover, this configuration could easily be changed negative bias by a using different Zener diode with the same 20 V isolated power supply. This configuration needs two isolated power supplies for a half-bridge configuration, but this scheme is very simple.

However, it has the disadvantage of having a steady state power consumption from  $R_{Zx}$ . Therefore, one should be careful in selecting the  $R_{Zx}$  values. It is recommended that  $R_{Zx}$  allow the minimal current flow to stabilize the Zener clamping voltage (e.g.  $I_Z$ : 5 mA~10 mA).

Typical recommended values are in the few kohm range (e.g. 1 k $\Omega$ ~2 k $\Omega$ ) of SiC MOSFETs application.

#### **Experimental Results**

Figure 58 show the experimental results of the negative bias with Zener diode on single isolated power supply of the NCP51561 for SiC MOSFET gate drive application. The examples were design to have a +15 V and -5.1 V drive power supply referenced to the device source by using the 20 V isolated power supply.



CH1: INPUT [2V/div], and CH2: OUTPUT [5 V/div]

Figure 58. Experimental Waveforms of Negative Bias with Zener Diode on Single Isolated Power Supply

#### **PCB Layout Guideline**

To improve the switching characteristics and efficiency of design, the following should be considered before beginning a PCB layout.

#### Component Placement

- Keep the input/output traces as short as possible.
   Minimize influence of the parasitic inductance and capacitance on the layout. (To maintain low signal-path inductance, avoid using via.)
- Placement and routing for supply bypass capacitors for V<sub>DD</sub> and V<sub>CC</sub>, and gate resistors need to be located as close as possible to the gate driver.
- The gate driver should be located switching device as close as possible to decrease the trace inductance and avoid output ringing.

#### Grounding Consideration

- Have a solid ground plane underneath the high-speed signal layer.
- Have a solid ground plane next to VSSA and VSSB pins with multiple VSSA and VSSB vias to reduce the parasitic inductance and minimize the ringing on the output signals.

#### High-Voltage (V<sub>ISO</sub>) Consideration

 To ensure isolation performance between the primary and secondary side, any PCB traces or copper should be not placed under the driver device as shown in Figure 59. A PCB cutout is recommended to avoid contamination that may impair the isolation performance of NCP51561.

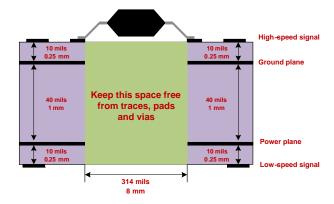
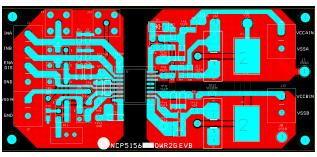
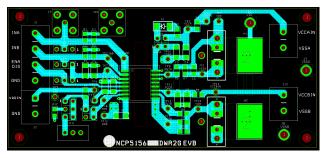


Figure 59. Recommended Layer Stack

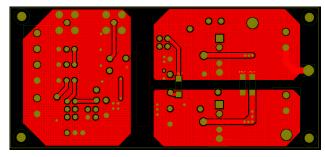
Figure 60 shows the printed circuit board layout of NCP51561 evaluation board.



(a) Top & Bottom View



(b) Top View



(c) Bottom View

Figure 60. Printed Circuit Board

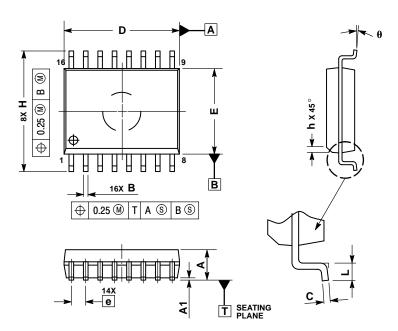
#### **ORDERING INFORMATION**

Device	Description	Package	UVLO	ENA/DIS	Shipping <sup>†</sup>
NCP51561BADWR2G	High current dual isolated MOS driver	SOIC-16 WB (Pb-Free)	8 V	ENABLE	1000 / Tape & Reel
NCP51561BBDWR2G	ulivei	SOIC-16 WB (Pb-Free)	8 V	DISABLE	1000 / Tape & Reel
NCP51561DADWR2G		SOIC-16 WB (Pb-Free)	17 V	ENABLE	1000 / Tape & Reel
NCP51561DBDWR2G		SOIC-16 WB (Pb-Free)	17 V	DISABLE	1000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

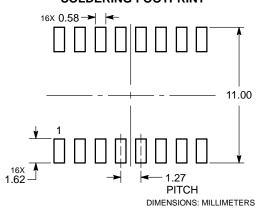
SOIC-16 WB CASE 751G-03 ISSUE D



- NOTES:
  1. DIMENSIONS ARE IN MILLIMETERS.
- INTERPRET DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
- DIMENSIONS D AND E DO NOT INLCUDE MOLD PROTRUSION.
- MOLD PROTRUSION.
  MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.
  DIMENSION B DOES NOT INCLUDE DAMBAR
  PROTRUSION. ALLOWABLE DAMBAR
  PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF THE B DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIMETERS				
DIM	MIN	MAX			
Α	2.35	2.65			
A1	0.10	0.25			
В	0.35	0.49			
С	0.23	0.32			
D	10.15	10.45			
Е	7.40	7.60			
е	1.27 BSC				
Н	10.05	10.55			
h	0.25	0.75			
L	0.50	0.90			
q	0 °	7 °			

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